

# 256K x 16 Static RAM

#### **Features**

- Temperature Ranges
  - Commercial: 0°C to 70°C
  - Industrial: –40°C to 85°C
  - Automotive-A: -40°C to 85°C
- High speed
  - t<sub>AA</sub> = 15 ns
- · Low active power
  - 1540 mW (max.)
- · Low CMOS standby power (L version)
  - 2.75 mW (max.)
- 2.0V Data Retention (400 μW at 2.0V retention)
- Automatic power-down when deselected
- · TTL-compatible inputs and outputs
- Easy memory expansion with CE and OE features
- Available in Pb-free and non Pb-free 44-pin TSOP II and molded 44-pin (400-Mil) SOJ packages

### **Functional Description**

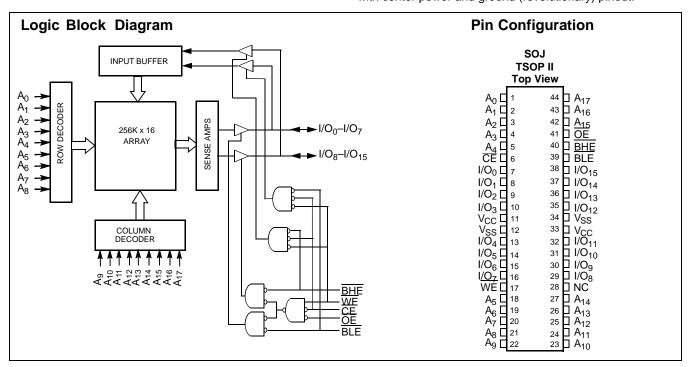
The CY7C1041BN is a high-performance CMOS static RAM organized as 262,144 words by 16 bits.

Writing to the device is accomplished by taking Chip Enable  $(\overline{\text{CE}})$  and Write Enable (WE) inputs LOW. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O $_0$  through I/O $_7$ ), is written into the location specified on the address pins (A $_0$  through A $_{17}$ ). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O $_8$  through I/O $_{15}$ ) is written into the location specified on the address pins (A $_0$  through A $_{17}$ ).

Reading from the device is accomplished by taking Chip Enable ( $\overline{\text{CE}}$ ) and Output Enable ( $\overline{\text{OE}}$ ) LOW while forcing the Write Enable ( $\overline{\text{WE}}$ ) HIGH. If Byte Low Enable ( $\overline{\text{BLE}}$ ) is LOW, then data from the memory location specified by the address pins will appear on I/O $_0$  to I/O $_7$ . If Byte High Enable ( $\overline{\text{BHE}}$ ) is LOW, then data from memory will appear on I/O $_8$  to I/O $_{15}$ . See the truth table at the back of this data sheet for a complete description of read and write modes.

The input/output pins (I/O $_0$  through I/O $_{15}$ ) are placed in a high-impedance state when the device is deselected (CE HIGH), the outputs are disabled (OE HIGH), the BHE and BLE are disabled (BHE, BLE HIGH), or during a write operation (CE LOW, and WE LOW).

The CY7C1041BN is available in a standard 44-pin 400-mil-wide body width SOJ and 44-pin TSOP II package with center power and ground (revolutionary) pinout.





#### **Selection Guide**

		-15	-20	Unit
Maximum Access Time		15	20	ns
Maximum Operating Current	Commercial	190	170	mA
	Industrial	210	190	
	Automotive-A		190	
Maximum CMOS Standby Current	Commercial	3	3	mA
	Commercial L	0.5	0.5	
	Industrial	6	6	
	Automotive-A		6	

## **Maximum Ratings**

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature .....-65°C to +150°C

Ambient Temperature with Power Applied......55°C to +125°C

Supply Voltage on  $V_{CC}$  to Relative  $GND^{[1]}$  .... –0.5V to +7.0V

DC Voltage Applied to Outputs in High Z State  $^{[1]}$  ......-0.5V to  $^{V}$  CC + 0.5V

DC Input Voltage <sup>[1]</sup>	0.5V to V <sub>CC</sub> + 0.5V
Current into Outputs (LOW)	20 mA

## **Operating Range**

Range	Ambient Temperature <sup>[2]</sup>	v <sub>cc</sub>
Commercial	0°C to +70°C	5V ± 0.5
Industrial	–40°C to +85°C	
Automotive-A	-40°C to +85°C	

## **Electrical Characteristics** Over the Operating Range

					-15		-20	
Parameter	Description	Test Condition	s	Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	$V_{CC} = Min., I_{OH} = -4.0 \text{ mA}$		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	$V_{CC} = Min., I_{OL} = 8.0 \text{ mA}$			0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage			2.2	V <sub>CC</sub> + 0.5	2.2	V <sub>CC</sub> + 0.5	V
V <sub>IL</sub>	Input LOW Voltage <sup>[1]</sup>				0.8	-0.5	0.8	V
I <sub>IX</sub>	Input Load Current	$GND \leq V_{I} \leq V_{CC}$	$SND \leq V_1 \leq V_{CC}$		+1	-1	+1	mA
l <sub>oz</sub>	Output Leakage Current	$GND \le V_{OUT} \le V_{CC}$ , Output	Disabled	-1	+1	-1	+1	mA
I <sub>CC</sub>	C V <sub>CC</sub> Operating Supply	$V_{CC} = Max.,$ $f = f_{MAX} = 1/t_{RC}$	Comm'l		190		170	mA
	Current		Ind'I		210		190	mA
			Auto-A				190	mA
I <sub>SB1</sub>	Automatic CE Power-Down Current—TTL Inputs	$\begin{aligned} &\text{Max. } V_{CC}, \overline{CE} \ge V_{IH}, V_{IN} \ge V_{IN} \le V_{IL}, f = f_{MAX} \end{aligned}$	/ <sub>IH</sub> or		40		40	mA
I <sub>SB2</sub>	Automatic CE	Max. $V_{CC}$ , $\overline{CE} \ge V_{CC} - 0.3V$ ,	Comm'l		3		3	mA
	Power-Down Current —CMOS Inputs	$V_{IN} \ge V_{CC} - 0.3V$ , or $V_{IN} \le 0.3V$ , f = 0	Comm'l L		0.5		0.5	mA
	Soo Inpaio	5. T <sub>IIV</sub> = 0.0 V, V = 0	Ind'I		6		6	mA
			Auto-A				6	mA

#### Notes:

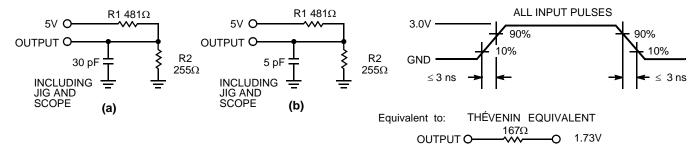
- 1.  $V_{IL}$  (min.) = -2.0V for pulse durations of less than 20 ns.
- T<sub>A</sub> is the case temperature.
   Tested initially and after any design or process changes that may affect these parameters.



## Capacitance<sup>[3]</sup>

Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C$ , $f = 1 \text{ MHz}$ ,	8	pF
C <sub>OUT</sub>	I/O Capacitance	$V_{CC} = 5.0V$	8	pF

#### **AC Test Loads and Waveforms**



## Switching Characteristics<sup>[4]</sup> Over the Operating Range

			15	-20			
Parameter	Description	Min. Max		Min.	Max.	Unit	
Read Cycle	·						
t <sub>power</sub> V <sub>CC</sub> (typical) to the First Access <sup>[5]</sup>		1		1		μS	
t <sub>RC</sub>	Read Cycle Time	15		20		ns	
t <sub>AA</sub>	Address to Data Valid		15		20	ns	
t <sub>OHA</sub>	Data Hold from Address Change	3		3		ns	
t <sub>ACE</sub> CE LOW to Data Valid			15		20	ns	
t <sub>DOE</sub>	OE LOW to Data Valid		7		8	ns	
t <sub>LZOE</sub>	OE LOW to Low Z	0		0		ns	
t <sub>HZOE</sub>	OE HIGH to High Z <sup>[6, 7]</sup>		7		8	ns	
t <sub>LZCE</sub>	CE LOW to Low Z <sup>[7]</sup>	3		3		ns	
t <sub>HZCE</sub>	CE HIGH to High Z <sup>[6, 7]</sup>		7		8	ns	
t <sub>PU</sub>	CE LOW to Power-Up	0		0		ns	
t <sub>PD</sub> CE HIGH to Power-Down			15		20	ns	
t <sub>DBE</sub>	Byte Enable to Data Valid		7		8	ns	
t <sub>LZBE</sub>	Byte Enable to Low Z	0		0		ns	
t <sub>HZBE</sub>	Byte Disable to High Z		7		8	ns	

#### Notes:

<sup>4.</sup> Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I<sub>OL</sub>/I<sub>OH</sub> and 30-pF load capacitance.

5. This part has a voltage regulator which steps down the voltage from 5V to 3.3V internally. t<sub>power</sub> time has to be provided initially before a read/write operation is

<sup>6.</sup> t<sub>HZOE</sub>, t<sub>HZCE</sub>, and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
7. At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZOE</sub> is less than t<sub>LZOE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any given device.



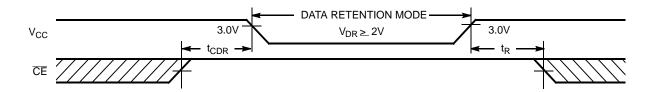
## **Switching Characteristics**<sup>[4]</sup> Over the Operating Range (continued)

			15	-20		
Parameter	Description	Description Min. Max.		Min.	Max.	Unit
Write Cycle <sup>[8, 9]</sup>						
WC Write Cycle Time		15		20		ns
t <sub>SCE</sub>	CE LOW to Write End	12		13		ns
t <sub>AW</sub>	Address Set-Up to Write End	12		13		ns
t <sub>HA</sub>	Address Hold from Write End			0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		ns
t <sub>PWE</sub>	WE Pulse Width	12		13		ns
t <sub>SD</sub>	Data Set-Up to Write End	8		9		ns
t <sub>HD</sub>	Data Hold from Write End			0		ns
t <sub>LZWE</sub>	ZWE WE HIGH to Low Z <sup>[7]</sup>			3		ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[6, 7]</sup>		7		8	ns
t <sub>BW</sub>	Byte Enable to End of Write	12		13		ns

## Data Retention Characteristics Over the Operating Range (L version only)

Parameter	Description	Conditions <sup>[11]</sup>	Min.	Max.	Unit
$V_{DR}$	V <sub>CC</sub> for Data Retention		2.0		V
I <sub>CCDR</sub>	Data Retention Current	$V_{CC} = V_{DR} = 2.0V,$		200	μΑ
t <sub>CDR</sub> <sup>[3]</sup>	Chip Deselect to Data Retention Time	$CE \ge V_{CC} - 0.3V$ , $V_{IN} \ge V_{CC} - 0.3V$ or $V_{IN} \le 0.3V$	0		ns
t <sub>R</sub> <sup>[10]</sup>	Operation Recovery Time		t <sub>RC</sub>		ns

## **Data Retention Waveform**



- 8. The internal write time of the memory is defined by the overlap of  $\overline{CE}$  LOW, and  $\overline{WE}$  LOW.  $\overline{CE}$  and  $\overline{WE}$  must be LOW to initiate a write, and the transition of either of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.

  9. The minimum write cycle time for Write Cycle no. 3 (WE controlled,  $\overline{OE}$  LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.

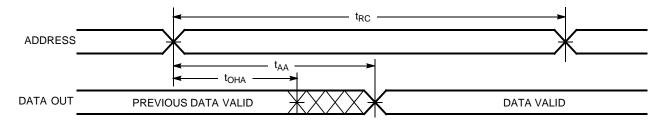
  10. t<sub>r</sub> ≤ 3 ns for the -15 speed. t<sub>r</sub> ≤ 5 ns for the -20 and slower speeds.

  11. No input may exceed V<sub>CC</sub> + 0.5V.

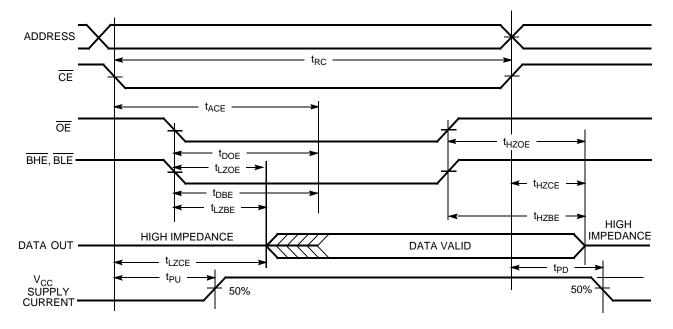


## **Switching Waveforms**

## Read Cycle No. $1^{[12, 13]}$



## Read Cycle No. 2 (OE Controlled)[13, 14]



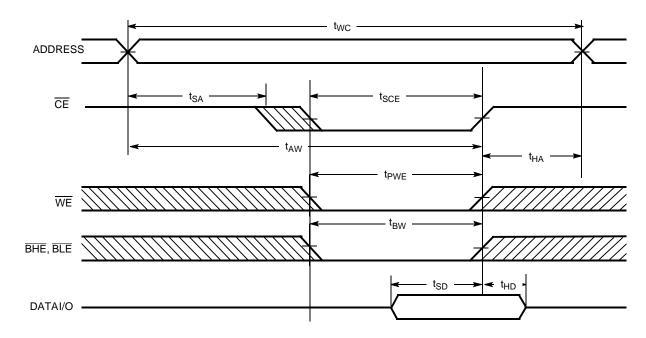
#### Notes:

- 12. <u>Device</u> is continuously selected. <u>OE</u>, <u>CE</u>, <u>BHE</u>, and/or <u>BHE</u> = V<sub>IL</sub>. 13. WE is HIGH for read cycle.
- 14. Address valid prior to or coincident with  $\overline{CE}$  transition LOW.

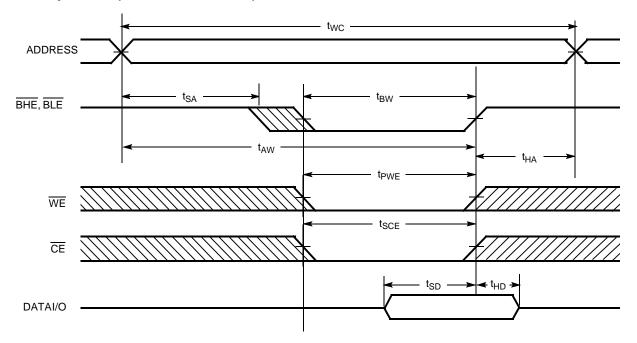


## **Switching Waveforms** (continued)

## Write Cycle No. 1 (CE Controlled)[15, 16]



## Write Cycle No. 2 (BLE or BHE Controlled)



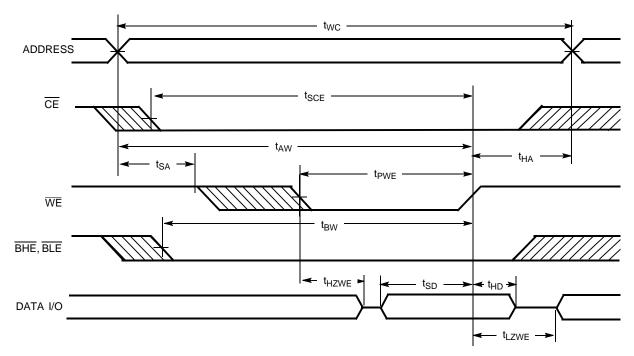
15. Data I/O is high impedance if  $\overline{OE}$  or  $\overline{BHE}$  and/or  $\overline{BLE} = V_{IH}$ .

16. If  $\overline{CE}$  goes HIGH simultaneously with  $\overline{WE}$  going HIGH, the output remains in a high-impedance state.



## Switching Waveforms (continued)

## Write Cycle No. 3 (WE Controlled, OE LOW)



## **Truth Table**

CE	OE	WE	BLE	BHE	I/O <sub>0</sub> –I/O <sub>7</sub>	I/O <sub>8</sub> –I/O <sub>15</sub>	Mode	Power
Н	Х	Х	Х	Х	High Z	High Z	Power Down	Standby (I <sub>SB</sub> )
L	L	Н	L	L	Data Out	Data Out	Read All bits	Active (I <sub>CC</sub> )
L	L	Н	L	Н	Data Out	High Z	Read Lower bits only	Active (I <sub>CC</sub> )
L	L	Н	Н	L	High Z	Data Out	Read Upper bits only	Active (I <sub>CC</sub> )
L	Х	L	L	L	Data In	Data In	Write All bits	Active (I <sub>CC</sub> )
L	Х	L	L	Н	Data In	High Z	Write Lower bits only	Active (I <sub>CC</sub> )
L	Х	L	Н	L	High Z	Data In	Write Upper bits only	Active (I <sub>CC</sub> )
L	Н	Н	Χ	Χ	High Z	High Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )



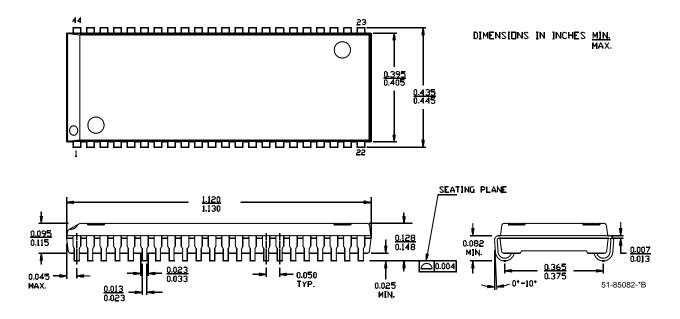
## **Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
15	CY7C1041BN-15VC	51-85082	44-pin (400-Mil) Molded SOJ	Commercial
	CY7C1041BN-15VXC		44-pin (400-Mil) Molded SOJ (Pb-free)	
	CY7C1041BN-15ZC	51-85087	44-pin TSOP Type II	
	CY7C1041BN-15ZXC		44-pin TSOP Type II (Pb-free)	
	CY7C1041BNL-15ZC		44-pin TSOP Type II	
	CY7C1041BNL-15ZXC		44-pin TSOP Type II (Pb-free)	
	CY7C1041BN-15ZI		44-pin TSOP Type II	Industrial
	CY7C1041BN-15ZXI		44-pin TSOP Type II (Pb-free)	
	CY7C1041BN-15VI	51-85082	44-pin (400-Mil) Molded SOJ	
	CY7C1041BN-15VXI		44-pin (400-Mil) Molded SOJ (Pb-free)	
20	CY7C1041BN-20VXC		44-pin (400-Mil) Molded SOJ (Pb-free)	Commercial
	CY7C1041BNL-20VXC		44-pin (400-Mil) Molded SOJ (Pb-free)	
	CY7C1041BN-20ZC	51-85087	44-pin TSOP Type II	
	CY7C1041BN-20ZXC		44-pin TSOP Type II (Pb-free)	
	CY7C1041BN-20ZI		44-pin TSOP Type II	Industrial
	CY7C1041BN-20ZXI		44-pin TSOP Type II (Pb-free)	
	CY7C1041BN-20VXI	51-85082	44-pin (400-Mil) Molded SOJ (Pb-free)	
	CY7C1041BN-20ZSXA	51-85087	44-pin TSOP Type II	Automotive-A

Please contact local sales representative regarding availability of these parts.

## **Package Diagrams**

## 44-pin (400-Mil) Molded SOJ (51-85082)

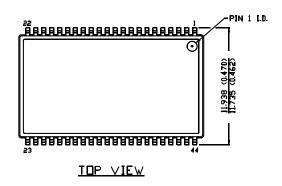


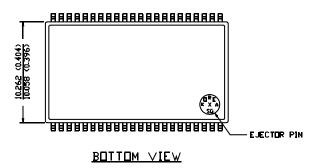


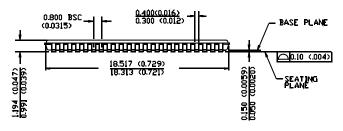
## Package Diagrams (continued)

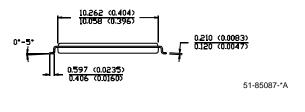
#### 44-Pin TSOP II (51-85087)

DIMENSION IN MM (INCH)









All products and company names mentioned in this document may be the trademarks of their respective holders.



# **Document History Page**

Document Title: CY7C1041BN 256K x 16 Static RAM Document Number: 001-06496					
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change	
**	424111	See ECN	NXR	New Data Sheets	
*A	498575	See ECN	NXR	Added Automotive-A operating range updated Ordering Information Table	